

Notice of References Cited

Application/Control No.

10/802,043

Applicant(s)/Patent Under
Reexamination
SIE ET AL.

Examiner

Ryan Stronczer

Art Unit

4157

Page 1 of 1

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| * | A | US-5,461,427 A | 10-1995 | Duffield et al. | 348/555 |
| * | B | US-5,598,276 A | 01-1997 | Cookson et al. | 386/46 |
| * | C | US-5,657,034 A | 08-1997 | Yamazaki, Yasuyuki | 345/8 |
| * | D | US-5,907,659 A | 05-1999 | Yamauchi et al. | 386/95 |
| * | E | US-6,169,568 B1 | 01-2001 | Shigetomi, Tetsu | 725/76 |
| * | F | US-2002/0056136 A1 | 05-2002 | Wistendahl et al. | 725/135 |
| * | G | US-2002/0059610 A1 | 05-2002 | Ellis, Michael D. | 725/58 |
| * | H | US-2003/0204844 A1 | 10-2003 | Brant et al. | 725/22 |
| * | I | US-2004/0123327 A1 | 06-2004 | Fai Ma et al. | 725/100 |
| * | J | US-7,061,552 B1 | 06-2006 | Patten et al. | 348/806 |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | | |
|---|---|---|--|--|--|--|
| | U | | | | | |
| | V | | | | | |
| | W | | | | | |
| | X | | | | | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.